


<b>Search Notes</b>  	<b>Application/Control No.</b>  10828443	<b>Applicant(s)/Patent Under Reexamination</b>  BAER, RICHARD
	<b>Examiner</b>  Koziol, Stephen R	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	115	3/14/2008	SRK

SEARCH NOTES		
Search Notes	Date	Examiner
NPL: IEEE explore and INSPEC search for biometric smart cards	3/14/2008	SRK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner